Sample Submission Form for Example Measurements

In order to provide the best and most appropriate measurement/results, the customer is asked to please fill in the following form and enclose it with the sample. **(на английском или русском языке)** This form or equivalent information is required prior to the sample measurements.

Customer Details:

Name: ______________________

E-Mail: ______________________

Phone: ______________________

Institution: ______________________

City, Country: ______________________

Fax: ______________________

Sample Description / Sample Properties:

☐ Transparent ☐ Opaque Dimensions: ______________ Substrate: ______________

General description of the samples (if necessary please also note aspects of storage, toxicity or general handling of the sample). If more than one samples are provided, please prioritize the different samples and identify clearly where on the sample the measurement should be performed:

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Requested Measurement Modes:

☐ Atomic Force Microscopy (AFM) ☐ AC Mode ☐ Pulsed Force Mode

☐ Confocal Raman Microscopy

☐ Scanning Near-field Optical Microscopy (SNOM) ☐ Other

Sample Preparation:

In general, the sample should be fully prepared for microscopic measurements. WITec can not provide specialised sample preparation.

Measurement Goal:

What's the goal of the measurement? If possible please provide existing images or spectra.

Как вы планируете использовать результаты:

☐ Представить в статье

☐ показать актуальность исследований

☐ подать заявку на грант

☐ подать заявку на закупку оборудования